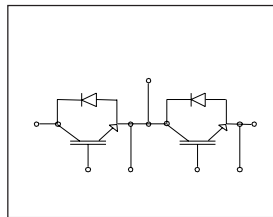


Features

- Generation 4 IGBT technology
- UltraFast: Optimized for high operating frequencies 8-40 kHz in hard switching, >200 kHz in resonant mode
- Very low conduction and switching losses
- HEXFRED™ antiparallel diodes with ultra-soft recovery
- Industry standard package
- UL approved



$$V_{CES} = 600V$$

$$V_{CE(on)} \text{ typ.} = 1.74V$$

$$@ V_{GE} = 15V, I_C = 200A$$

Benefits

- Increased operating efficiency
- Direct mounting to heatsink
- Performance optimized for power conversion: UPS, SMPS, Welding
- Low EMI, requires less snubbing



Absolute Maximum Ratings

| Parameters | | Max | Units |
|------------|--|----------------------------|-------|
| V_{CES} | Collector-to-Emitter Voltage | 600 | V |
| I_C | Continuous Collector Current @ $T_C = 25^\circ\text{C}$ | 265 | A |
| I_{CM} | Pulsed Collector Current | 400 | |
| I_{LM} | Peak Switching Current | 400 | |
| I_{FM} | Peak Diode Forward Current | 400 | |
| V_{GE} | Gate-to-Emitter Voltage | ± 20 | V |
| V_{ISOL} | RMS Isolation Voltage, Any Terminal to Case, $t = 1 \text{ min}$ | 2500 | |
| P_D | Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$ | 625 | W |
| | | @ $T_C = 85^\circ\text{C}$ | |

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

| Parameters | | Min | Typ | Max | Units | Test Conditions |
|---------------------------------------|--|-----|-------|-------|-------|--|
| V _{BRCES} | Collector-to-Emitter Breakdown Voltage | 600 | | | V | V _{GE} = 0V, I _C = 1mA |
| V _{CE(on)} | Collector-to-Emitter Voltage | | 1.74 | 2.2 | | V _{GE} = 15V, I _C = 200A |
| | | | 1.79 | 2.25 | | V _{GE} = 15V, I _C = 200A, T _J = 125°C |
| V _{GE(th)} | Gate Threshold Voltage | 3 | 4.4 | 6 | | I _C = 0.25mA |
| ΔV _{GE(th)} /ΔT _J | Temperat. Coeff. of Threshold Voltage | | - 11 | | mV/°C | V _{CE} = V _{GE} , I _C = 0.25mA |
| g _{fe} | Forward Transconductance | | 220 | | S | V _{CE} = 20V, I _C = 200A |
| I _{CES} | Collector-to-Emitter Leakage Current | | 0.014 | 1 | mA | V _{GE} = 0V, V _{CE} = 600V |
| | | | | 10 | | V _{GE} = 0V, V _{CE} = 600V, T _J = 125°C |
| V _{FM} | Diode Forward Voltage drop | | 4.2 | 6.0 | V | I _C = 200A, V _{GE} = 0V |
| | | | 4.4 | 6.2 | | I _C = 200A, V _{GE} = 0V, T _J = 125°C |
| I _{GES} | Gate-to-Emitter Leakage Current | | | ± 250 | nA | V _{GE} = ± 20V |

Switching Characteristics @ T_J = 25°C (unless otherwise specified)

| Parameters | | Min | Typ | Max | Units | Test Conditions |
|-------------------------|---|-----|-------|-----|-------|---|
| Q _g | Total Gate Charge | | 900 | | nC | I _C = 200A |
| Q _{ge} | Gate-Emitter Charge | | 125 | | | I _C = 270A, V _{GE} = 15V |
| Q _{gc} | Gate-Collector Charge | | 306 | | | |
| t _{d(on)} | Turn-On Delay Time | | 342 | | ns | I _C = 200A V _{CC} = 360V V _{GE} = ±15V T _J = 125°C |
| t _r | Rise Time | | 194 | | | |
| t _{d(off)} | Turn-Off Delay Time | | 366 | | | |
| t _f | Fall Time | | 213 | | | |
| E _{on} | Turn-On Switching Energy | | 5 | | mJ | |
| E _{off} | Turn-Off Switching Energy | | 16 | | | R _{G1} = 15Ω |
| E _{ts} | Total Switching Energy | | 21 | | | R _{G2} = 0Ω |
| C _{ies} | Input Capacitance | — | 20068 | — | | V _{GE} = 0V |
| C _{oes} | Output Capacitance | — | 1254 | — | pF | V _{CC} = 30V |
| C _{res} | Reverse Transfer Capacitance | — | 261 | — | | f = 1 MHz |
| t _{rr} | Diode Reverse Recovery Time | — | 179 | — | ns | I _C = 200A |
| I _{rr} | Diode Peak Reverse Current | — | 120 | — | A | V _{CC} = 360V |
| Q _{rr} | Diode Recovery Charge | — | 10714 | — | μC | di/dt = 1300A/μs |
| di _(rec) /dt | Diode Peak Rate of Fall of Recovery During t _b | — | 1922 | — | A/μs | |

Thermal- Mechanical Specifications

| Parameters | | Min | Typ | Max | Units |
|-------------------|--------------------------------------|--------------------------|-----|-----|-------|
| T _J | Operating Junction Temperature Range | - 40 | | 150 | °C |
| T _{STG} | Storage Temperature Range | - 40 | | 125 | |
| R _{thJC} | Junction-to-Case | IGBT | | 0.2 | °C/ W |
| | | Per Diode | | 0.4 | |
| R _{thCS} | Case-to-Sink | | 0.1 | | |
| T | Mounting torque | Case to heatsink | | 6 | Nm |
| | | Case to terminal 1, 2, 3 | | 5 | |
| | Weight | | 200 | | g |

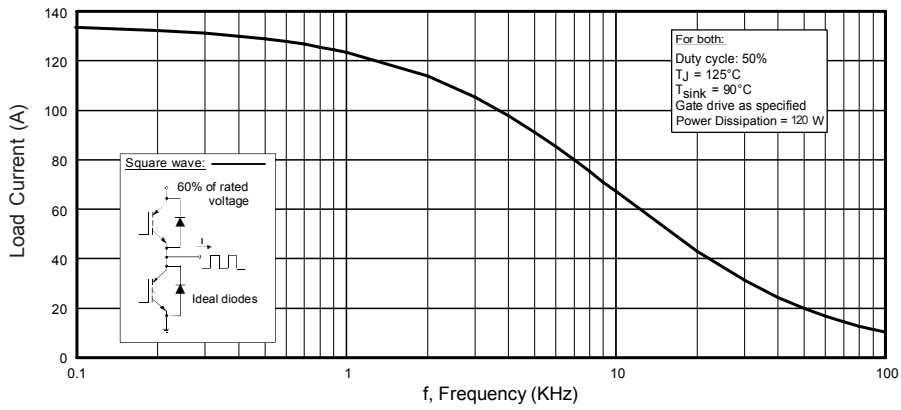


Fig. 1 - Typical Load Current vs. Frequency
 (Load Current = I_{RMS} of fundamental)

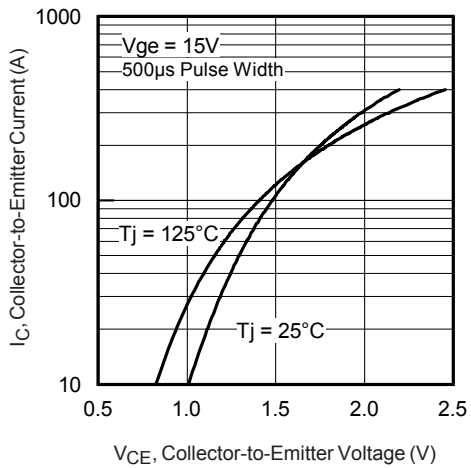


Fig. 2 - Typical Output Characteristics

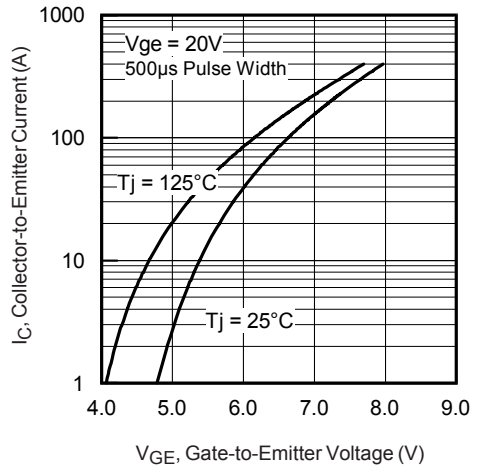


Fig. 3 - Typical Transfer Characteristics

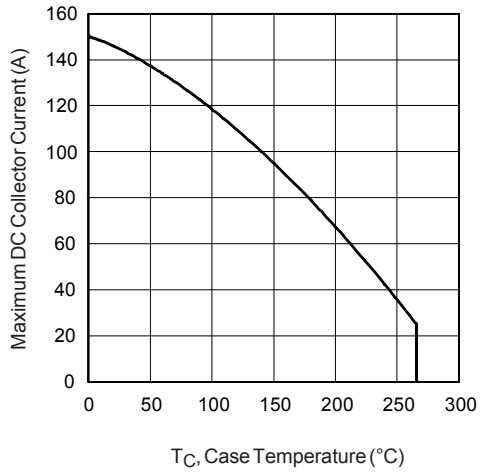


Fig. 4 - Maximum Collector Current vs. Case Temperature

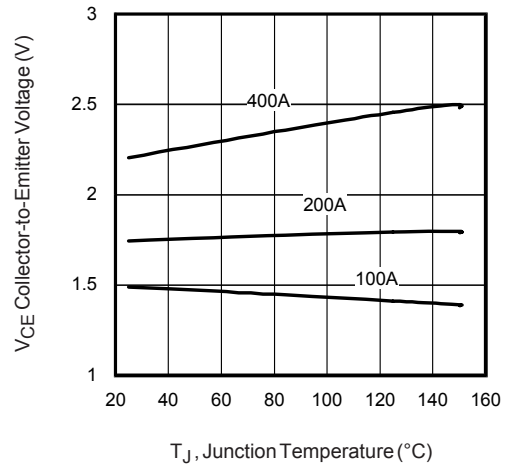


Fig. 5 - Typical Collector-to-Emitter Voltage vs. Junction Temperature

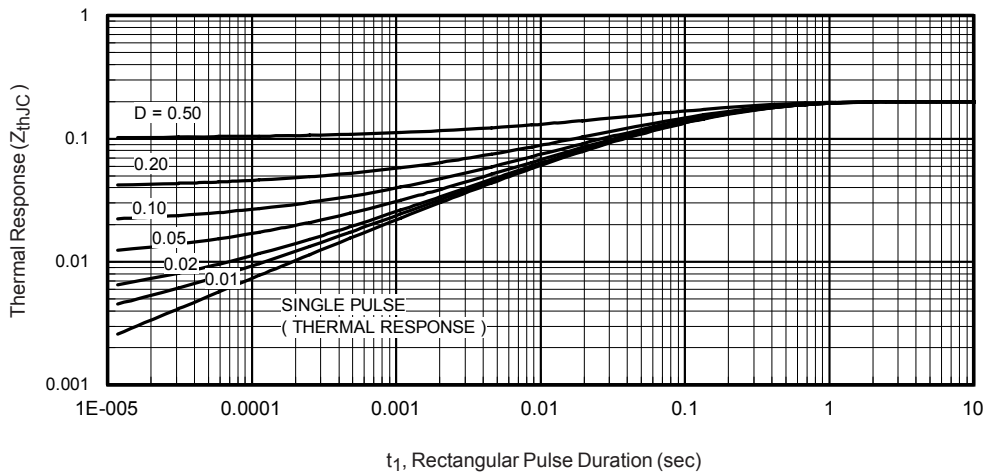


Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

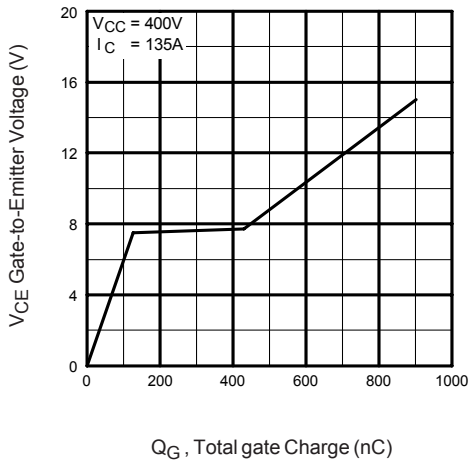


Fig. 7 - Typical Gate Charge vs. Gate-to-Emitter Voltage

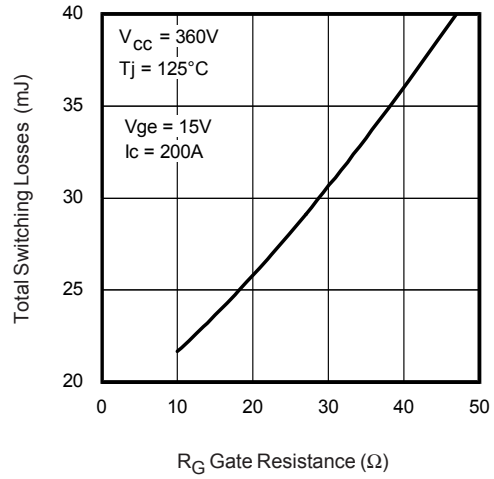


Fig. 8 - Typ. Switching Losses vs. Gate Resistance

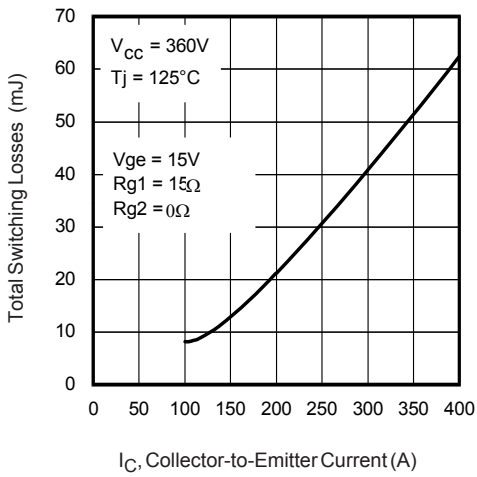


Fig. 9 - Typ. Switching Losses vs. Collector-to-Emitter Current

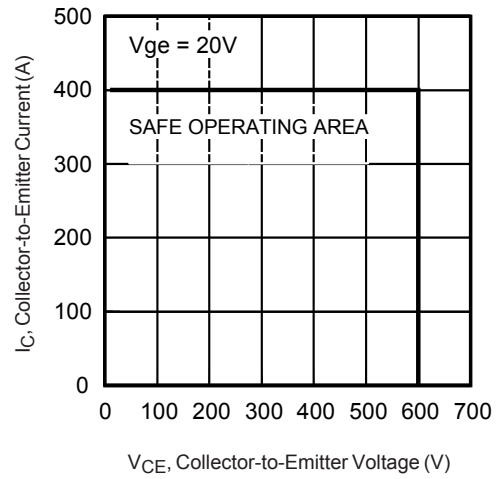


Fig. 10 - Reverse Bias SOA

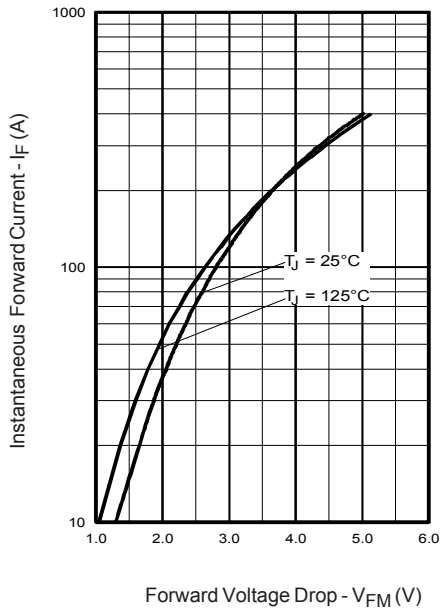


Fig. 11 - Typ. Forward Voltage Drop vs. Instantaneous Forward Current

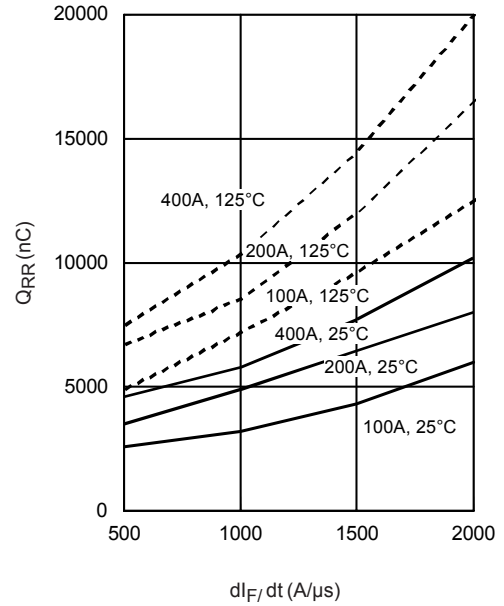


Fig. 12 - Typical Stored Charge vs. di_f/dt

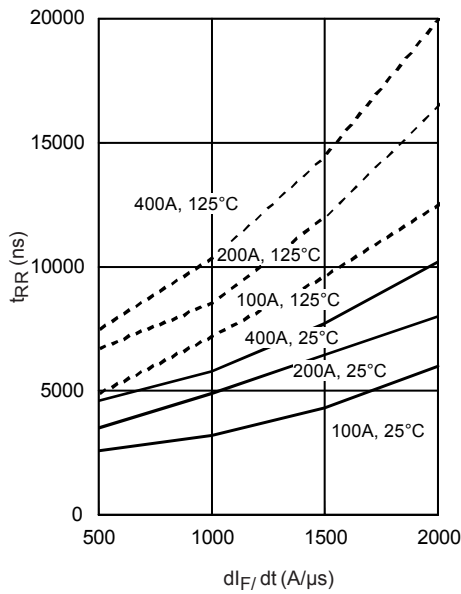


Fig. 13 - Typical Reverse Recovery vs. di_f/dt

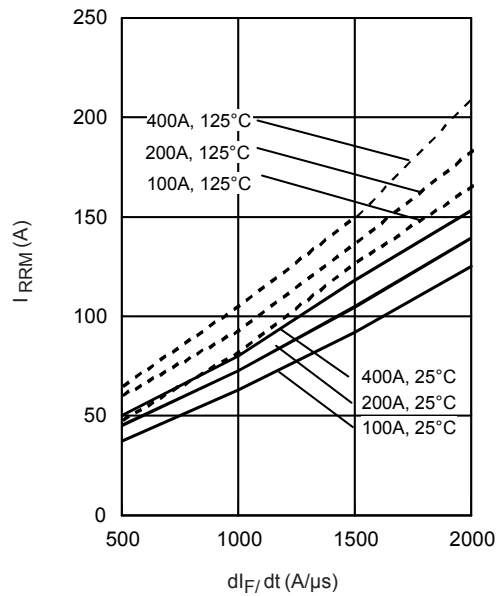


Fig. 14 - Typical Reverse Recovery vs. di_f/dt

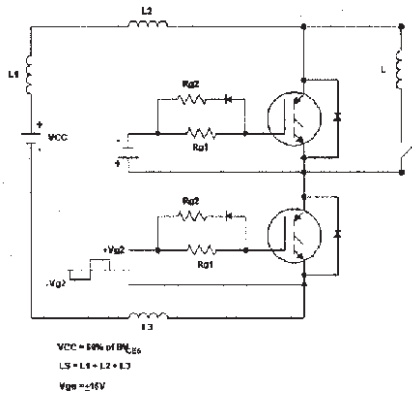


Fig. 15a - Test Circuit for Measurement of I_{LM} ,
 E_{on} , $E_{off}(\text{diode})$, t_{rr} , Q_{rr} , I_{rr} , $t_{d(on)}$, t_r , $t_{d(off)}$, t_f

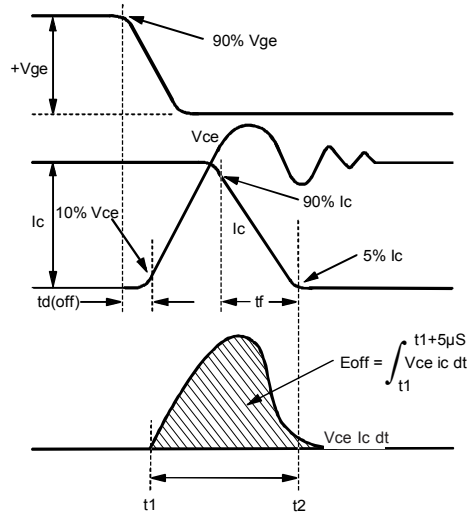


Fig. 15b - Test Waveforms for Circuit of Fig. 18a, Defining
 E_{off} , $t_{d(off)}$, t_f

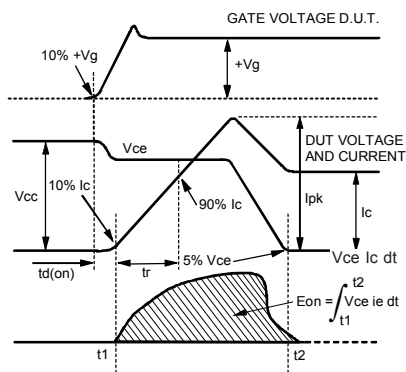


Fig. 15c - Test Waveforms for Circuit of Fig. 18a,
 Defining E_{on} , $t_{d(on)}$, t_r

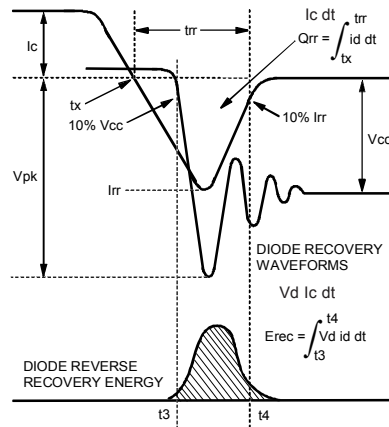


Fig. 15d - Test Waveforms for Circuit of Fig. 18a,
 Defining E_{rec} , t_{rr} , Q_{rr} , I_{rr}

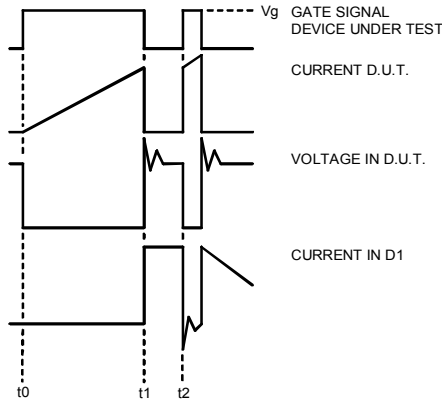


Figure 15e. Macro Waveforms for Figure 18a's Test Circuit

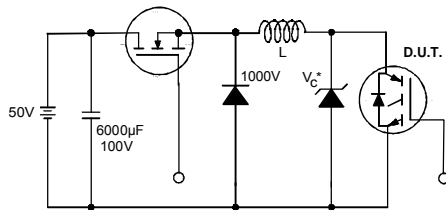


Figure 16. Clamped Inductive Load Test Circuit

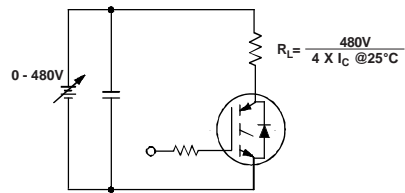
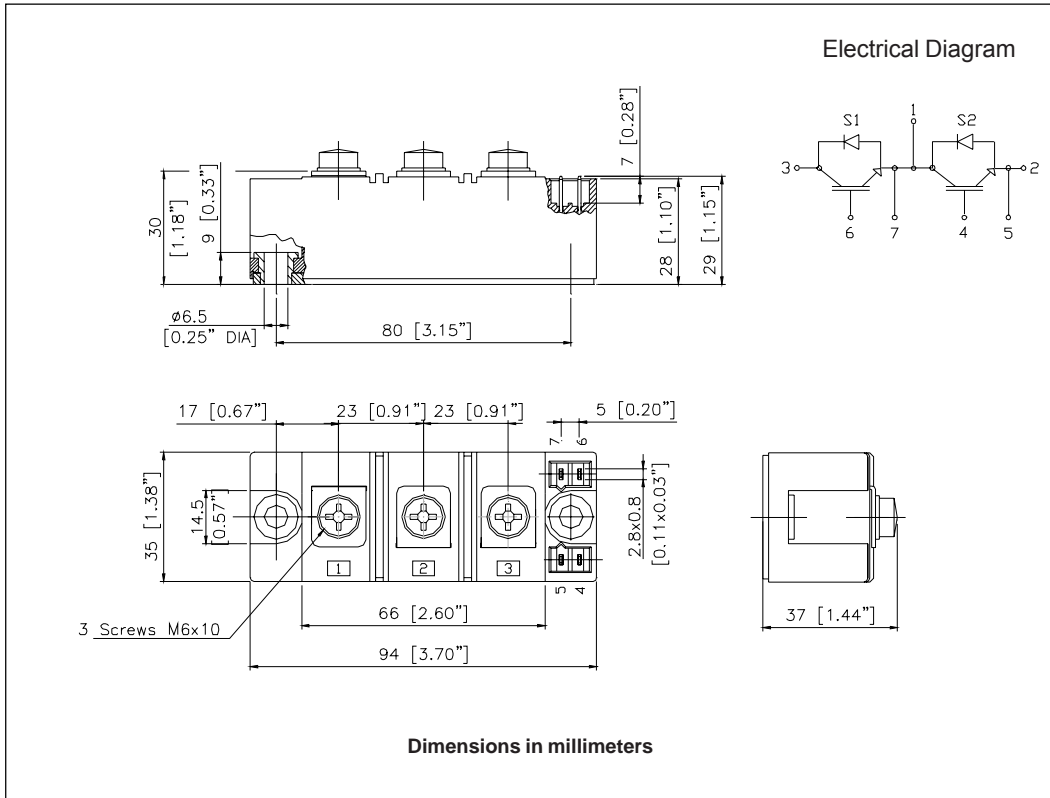


Figure 17. Pulsed Collector Current Test Circuit

Outline Table



Data and specifications subject to change without notice.
 This product has been designed and qualified for Industrial Level.
 Qualification Standards can be found on IR's Web site.



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